Code No: R15A0410

MALLA REDDY COLLEGE OF ENGINEERING & TECHNOLOGY

(Autonomous Institution – UGC, Govt. of India)

III B.Tech I Semester Supplementary Examinations, April 2023 Digital Design Through Verilog

(ECE)											
Roll No											

Time: 3 hours Max. Marks: 75

Note: This question paper contains two parts A and B

Part A is compulsory which carriers 25 marks and Answer all questions.

Part B Consists of 5 SECTIONS (One SECTION for each UNIT). Answer FIVE Questions, Choosing ONE Question from each SECTION and each Question carries 10 marks.

PART-A (25 Marks)

1). a	Define Verilog HDL.	[2M]
b	What is Module?	[3M]
c	What is AND gate primitive?	[2M]
d	Define strengths and content resolution.	[3M]
e	What is initial construct?	[2M]
f	Explain force-release construct.	[3M]
g	Explain tranif1 and tranif0.	[2M]
h	Define module path.	[3M]
i	What is capacitive model?	[2M]
j	Explain about Testbench?	[3M]
·	PART-B (50 MARKS)	
	SECTION-I	
2	a) Differentiate between synthesis and simulation.	[5M]
	b) Explain levels of abstraction in digital design with examples.	[5M]
	OR	
3	Explain the following:	
	a) Programming Language interface	[5M]
	b) Functional verification	[5M]
	SECTION-II	
4	a) Explain continuous assignments and strengths with example	[5M]
	b) Explain delays with continuous assignments	[5M]
	OR	
5	a) Write short notes on Tri state gates and delays associated with them.	[5M]
	b) Write Verilog code and test bench of 4 to 1 multiplexer using ternary	[5M]
	operator.	
	SECTION-III	
6	a) Write Verilog description of JK flip flop with preset and clear facility.	[5M]
	b) Differentiate between blocking and nonblocking assignments with	[5M]
	examples.	
	OR	
7	Write Verilog code to model ALU and write the test bench for the same.	[10M]

SECTION-IV

8 Explain in detail about Basic switch primitives and resistive switches.

OR

9 Design a half adder module with time delay assignment through parameter declaration and write the test bench for the same.

SECTION-V

10 Write short notes on sequential models.

OR

11 Differentiate between combinational circuits testing and sequential circuits testing.

[10M]
